

# FQP27P06 P-Channel QFET<sup>®</sup> MOSFET - 60 V, - 27 A, 70 mΩ

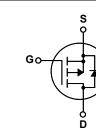
### Description

This P-Channel enhancement mode power MOSFET is produced using Fairchild Semiconductor<sup>®</sup>'s proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, audio amplifier, DC motor control, and variable switching power applications.

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### Features

- + 27 A, 60 V,  $R_{DS(on)}$  = 70 m $\Omega$  (Max.) @  $V_{GS}$  = 10 V,  $I_{D}$  = 13.5 A
- Low Gate Charge (Typ. 33 nC)
- Low Crss (Typ. 120 pF)
- 100% Avalanche Tested
- 175°C Maximum Junction Temperature Rating



## Absolute Maximum Ratings T<sub>c</sub> = 25°C unless otherwise noted

| Symbol                            | Parameter   |                                   |          | FQP27P06    | Unit |
|-----------------------------------|---|-----------------------------------|----------|-------------|------|
| V <sub>DSS</sub>                  | Drain-Source V  | oltage                            |          | -60         | V    |
| I <sub>D</sub>                    | Drain Current   | - Continuous (T <sub>C</sub> = 25 | °C)      | -27         | A    |
|                                   |   | - Continuous (T <sub>C</sub> = 10 | O°C)     | -19.1       | А    |
| I <sub>DM</sub>                   | Drain Current   | - Pulsed                          | (Note 1) | -108        | A    |
| V <sub>GSS</sub>                  | Gate-Source Voltage   |                                   |          | $\pm 25$    | V    |
| E <sub>AS</sub>                   | Single Pulsed Avalanche Energy  |                                   | (Note 2) | 560         | mJ   |
| I <sub>AR</sub>                   | Avalanche Current   |                                   | (Note 1) | -27         | A    |
| E <sub>AR</sub>                   | Repetitive Avalanche Energy   |                                   | (Note 1) | 12          | mJ   |
| dv/dt                             | Peak Diode Recovery dv/dt   |                                   | (Note 3) | -7.0        | V/ns |
| PD                                | Power Dissipation (T <sub>C</sub> = 25°C)                                     |                                   |          | 120         | W    |
|                                   | - Derate above 25°C   |                                   |          | 0.8         | W/°C |
| T <sub>J</sub> , T <sub>STG</sub> | Operating and Storage Temperature Range                                       |                                   |          | -55 to +175 | °C   |
| TL                                | Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds |                                   |          | 300         | °C   |
| 'L                                |   |                                   |          | 300         | U    |

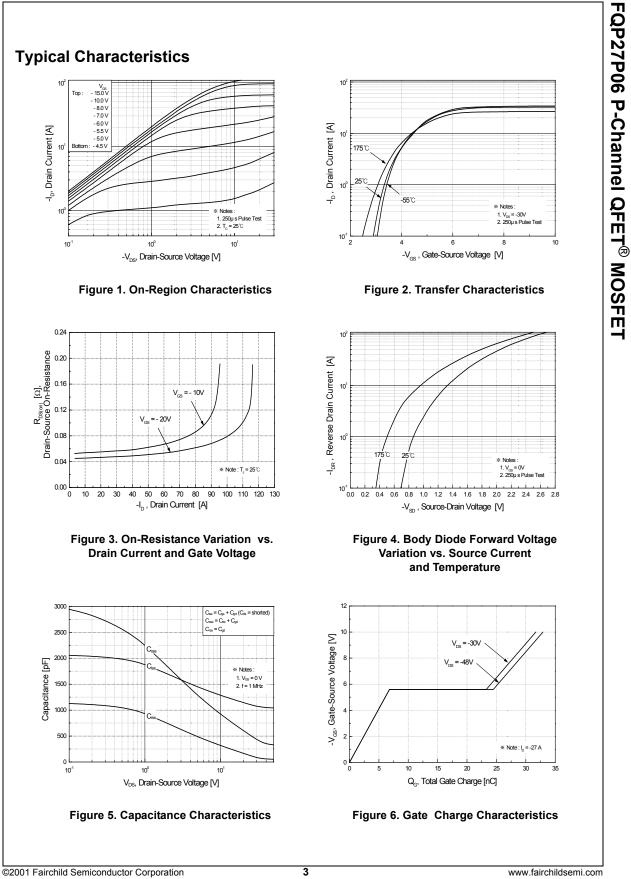
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### **Thermal Characteristics**

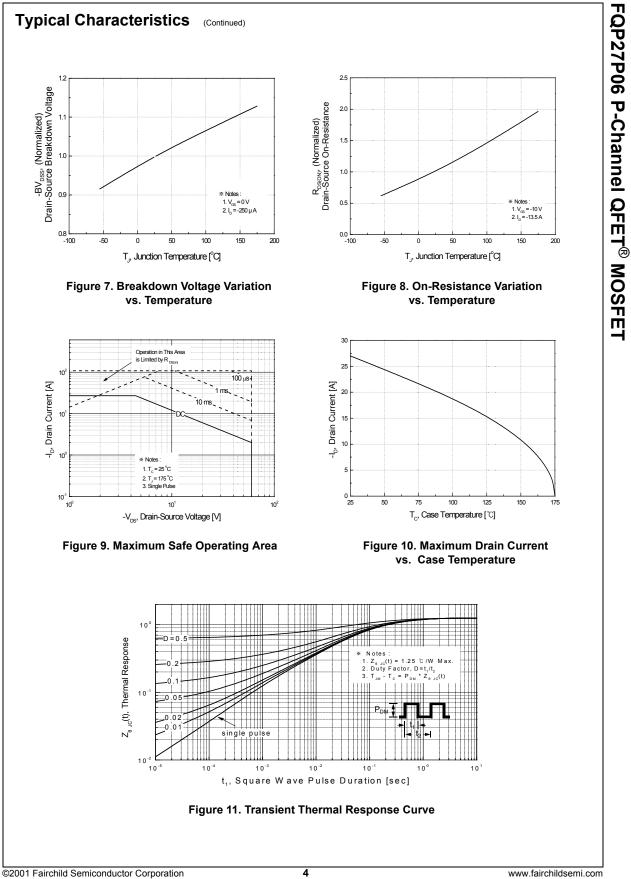
| Symbol              | Parameter                                     | FQP27P06 | Unit<br>°C/W |  |
|---------------------|---|----------|--------------|--|
| $R_{	ext{	heta}JC}$ | Thermal Resistance, Junction-to-Case, Max.    | 1.25     |              |  |
| $R_{\theta CS}$     | Thermal Resistance, Case-to-Sink, Typ.        | 0.5      | °C/W         |  |
| $R_{	hetaJA}$       | Thermal Resistance, Junction-to-Ambient, Max. | 62.5     | °C/W         |  |

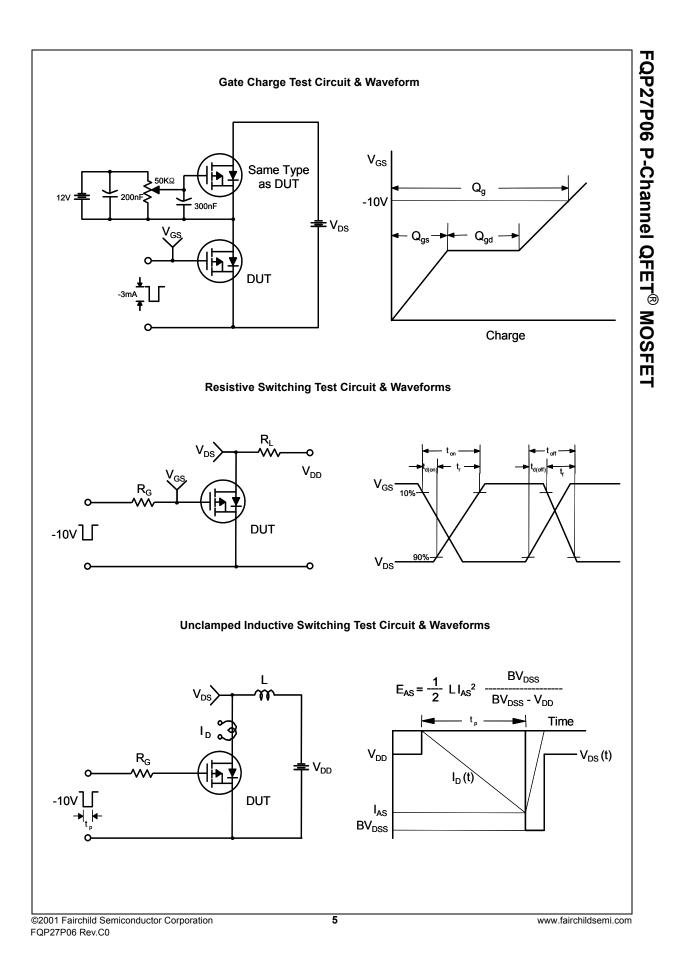
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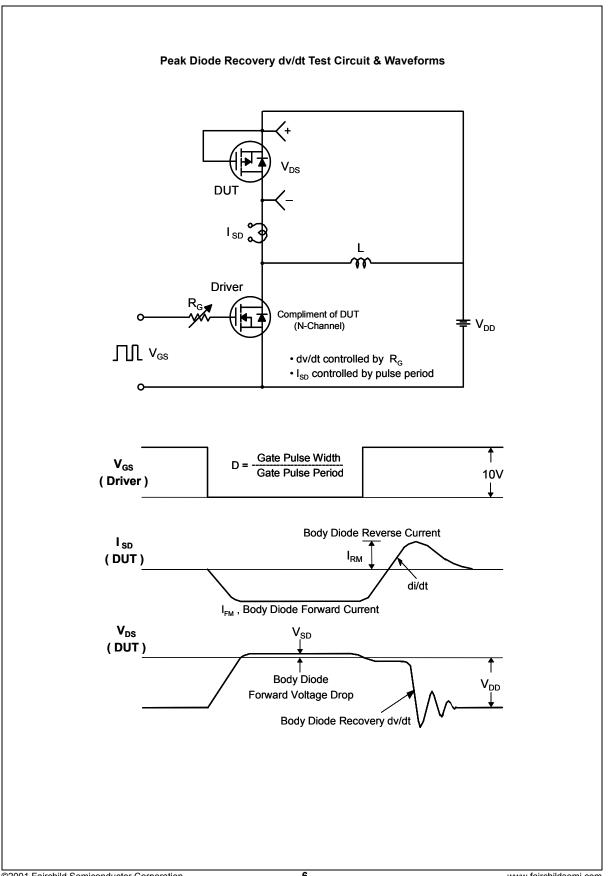
| Parameter   | Test Conditions   | Min   | Тур   | Max   | Unit  |
|---|---|---|---|---|---|
| iracteristics   |   |   |   |   |   |
|   | V <sub>GS</sub> = 0 V, I <sub>D</sub> = -250 μA   | -60   |   |   | V   |
| Breakdown Voltage Temperature<br>Coefficient                                      |   | C   | -0.06   |   | V/°C  |
|   | V <sub>DS</sub> = -60 V, V <sub>GS</sub> = 0 V  |   |   | -1  | μA  |
| Zero Gate Voltage Drain Current   | V <sub>DS</sub> = -48 V, T <sub>C</sub> = 150°C   |   |   | -10   | μA  |
| Gate-Body Leakage Current, Forward $V_{GS} = -25 \text{ V}, V_{DS} = 0 \text{ V}$ |   |   |   | -100  | nA  |
| Gate-Body Leakage Current, Reverse  | $V_{GS}$ = 25 V, $V_{DS}$ = 0 V   |   |   | 100   | nA  |
| racteristics  |   |   |   |   |   |
|   | V <sub>DS</sub> = V <sub>GS</sub> , I <sub>D</sub> = -250 μA  | -2.0  |   | -4.0  | V   |
| Static Drain-Source<br>On-Resistance  | •   |   | 0.055   | 0.07  | Ω   |
| Forward Transconductance  |   |   | 12.4  |   | S   |
| ic Characteristics  | ,   |   |   |   |   |
| Input Capacitance   | V <sub>DS</sub> = -25 V, V <sub>GS</sub> = 0 V,   |   | 1100  | 1400  | pF  |
| Output Capacitance  | f = 1.0 MHz   |   | 510   | 660   | pF  |
| Reverse Transfer Capacitance  |   |   | 120   | 155   | pF  |
| ng Characteristics  |   |   |   |   |   |
| Turn-On Delay Time  | Vpp = -30 V. lp = -13.5 A.  |   | 18  | 45  | ns  |
| Turn-On Rise Time   |   |   | 185   | 380   | ns  |
| Turn-Off Delay Time   | 0   |   | 30  | 70  | ns  |
| Turn-Off Fall Time  | (Note 4   | )   | 90  | 190   | ns  |
| Total Gate Charge   | V <sub>DS</sub> = -48 V, I <sub>D</sub> = -27 A,  |   | 33  | 43  | nC  |
| Gate-Source Charge  | V <sub>GS</sub> = -10 V   |   | 6.8   |   | nC  |
| Gate-Drain Charge   | (Note 4   | )   | 18  |   | nC  |
|   |   |   |   |   |   |
| ource Diode Characteristics a   | nd Maximum Ratings  |   |   |   |   |
| ource Diode Characteristics a   |   |   |   | -27   | А   |
|   | ode Forward Current   |   |   | -27<br>-108   | A   |
| Maximum Continuous Drain-Source Dio<br>Maximum Pulsed Drain-Source Diode R        | ode Forward Current   |   |   |   |   |
| Maximum Continuous Drain-Source Die   | ode Forward Current   | <br><br>  |   | -108  | А   |
|   | Coefficient<br>Zero Gate Voltage Drain Current<br>Gate-Body Leakage Current, Forward<br>Gate-Body Leakage Current, Reverse<br><b>racteristics</b><br>Gate Threshold Voltage<br>Static Drain-Source<br>On-Resistance<br>Forward Transconductance<br><b>ic Characteristics</b><br>Input Capacitance<br>Output Capacitance<br>Reverse Transfer Capacitance<br><b>ing Characteristics</b><br>Turn-On Delay Time<br>Turn-On Rise Time<br>Turn-Off Delay Time<br>Turn-Off Fall Time | Drain-Source Breakdown Voltage $V_{GS} = 0 \text{ V}, \text{ I}_D = -250 \text{ μA}$ Breakdown Voltage Temperature<br>Coefficient $\text{I}_D = -250 \text{ μA}, \text{ Referenced to } 25^{\circ} \text{ M}$ Zero Gate Voltage Drain Current $V_{DS} = -60 \text{ V}, V_{GS} = 0 \text{ V}$ Qate-Body Leakage Current, Forward $V_{GS} = -25 \text{ V}, V_{DS} = 0 \text{ V}$ Gate-Body Leakage Current, Reverse $V_{GS} = 25 \text{ V}, V_{DS} = 0 \text{ V}$ <b>racteristics</b> $V_{GS} = 25 \text{ V}, V_{DS} = 0 \text{ V}$ Gate Threshold Voltage $V_{DS} = V_{GS}, \text{ I}_D = -250 \text{ μA}$ Static Drain-Source<br>On-Resistance $V_{GS} = -10 \text{ V}, \text{ I}_D = -13.5 \text{ A}$ Forward Transconductance $V_{DS} = -30 \text{ V}, \text{ I}_D = -13.5 \text{ A}$ <b>ic Characteristics</b> Input CapacitanceInput Capacitance $V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V}, \text{ f} = 1.0 \text{ MHz}$ Reverse Transfer Capacitance $V_{DD} = -30 \text{ V}, \text{ I}_D = -13.5 \text{ A}, \text{ R}_G = 25 \Omega$ Turn-On Delay Time<br>Turn-Off Delay Time $V_{DD} = -30 \text{ V}, \text{ I}_D = -13.5 \text{ A}, \text{ R}_G = 25 \Omega$ | $\begin{array}{ c c c c } \hline Drain-Source Breakdown Voltage & V_{GS} = 0 \ V, \ I_D = -250 \ \mu A & -60 \\ \hline Breakdown Voltage Temperature \\ Coefficient & I_D = -250 \ \mu A, Referenced to 25^{\circ}C & \\ \hline V_{DS} = -60 \ V, \ V_{GS} = 0 \ V & \\ \hline V_{DS} = -48 \ V, \ T_C = 150^{\circ}C & \\ \hline Gate-Body \ Leakage Current, Forward & V_{GS} = -25 \ V, \ V_{DS} = 0 \ V & \\ \hline Gate-Body \ Leakage Current, Reverse & V_{GS} = 25 \ V, \ V_{DS} = 0 \ V & \\ \hline Gate-Body \ Leakage Current, Reverse & V_{GS} = 25 \ V, \ V_{DS} = 0 \ V & \\ \hline \ Gate-Body \ Leakage Current, Reverse & V_{GS} = 25 \ V, \ V_{DS} = 0 \ V & \\ \hline \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \$ | $\begin{array}{c c c c c c c c } \hline Drain-Source Breakdown Voltage & V_{GS} = 0 \ V, \ I_D = -250 \ \mu A & -60 & & -60 \ I_D = -250 \ \mu A, \ Referenced to 25^{\circ}C & & -0.06 \ V_{DS} = -60 \ V, \ V_{GS} = 0 \ V & & & \ V_{DS} = -48 \ V, \ T_C = 150^{\circ}C & & & \ V_{DS} = -48 \ V, \ T_C = 150^{\circ}C & & & \ Gate-Body \ Leakage \ Current, \ Forward & V_{GS} = -25 \ V, \ V_{DS} = 0 \ V & & \ Gate-Body \ Leakage \ Current, \ Reverse & V_{GS} = 25 \ V, \ V_{DS} = 0 \ V & & \ Tacteristics \ Gate \ Threshold \ Voltage \ V_{DS} = V_{GS}, \ I_D = -250 \ \mu A & -2.0 & \ Static \ Drain-Source & V_{GS} = -10 \ V, \ I_D = -13.5 \ A & & 0.055 \ Forward \ Transconductance & V_{DS} = -30 \ V, \ I_D = -13.5 \ A & & 12.4 \ Tacteristics \ Input \ Capacitance & V_{DS} = -25 \ V, \ V_{GS} = 0 \ V, \ I_D = -13.5 \ A & & 120 \ Tacteristics \ Turn-On \ Delay \ Time & V_{DD} = -30 \ V, \ I_D = -13.5 \ A, \ Iurn-On \ Delay \ Time \ Turn-On \ Delay \ Time \ V_{DD} = -30 \ V, \ I_D = -13.5 \ A, \ Iurn-On \ Rise \ Time \ V_{DD} = -30 \ V, \ I_D = -13.5 \ A, \ Iurn-On \ Rise \ Time \ R_G = 25 \ \Omega & (Note 4) \ Iurn \ 185 \ Iurn-Off \ Fall \ Time \ (Note 4) \ Iurn \ 90 \ Iurn \ V_{DD} = -13.5 \ A \ Iurn \ V_{DD} = -13.5 \ A, \ Iurn-Off \ Fall \ Time \ V_{DD} = -30 \ V, \ I_D = -13.5 \ A, \ Iurn-Off \ Fall \ Time \ V_{DD} = -30 \ V, \ I_D = -13.5 \ A, \ Iurn-Off \ Table \ V_{DD} = -30 \ V, \ I_D = -13.5 \ A, \ Iurn-Off \ Table \ V_{DD} = -30 \ V, \ I_D = -13.5 \ A, \ Iurn-Off \ Table \ V_{DD} = -30 \ V, \ I_D = -30 \ V, \$ | $\begin{array}{c c c c c c c c } \hline Drain-Source Breakdown Voltage & V_{GS} = 0 \ V, \ I_D = -250 \ \mu A & -60 & & & -1 \\ \hline Breakdown Voltage Temperature & I_D = -250 \ \mu A, \ Referenced to 25^{\circ}C & & -0.06 & & & -1 \\ \hline V_{DS} = -60 \ V, \ V_{GS} = 0 \ V & & & -1 & -1 \\ \hline V_{DS} = -48 \ V, \ T_C = 150^{\circ}C & & & -1 & -1 \\ \hline Gate-Body \ Leakage \ Current, \ Forward & V_{GS} = -25 \ V, \ V_{DS} = 0 \ V & & & -1 & -1 \\ \hline Gate-Body \ Leakage \ Current, \ Reverse & V_{GS} = 25 \ V, \ V_{DS} = 0 \ V & & & -1 & -1 \\ \hline Gate-Body \ Leakage \ Current, \ Reverse & V_{GS} = 25 \ V, \ V_{DS} = 0 \ V & & & -1 & -1 \\ \hline Gate \ Threshold \ Voltage & V_{DS} = V_{GS}, \ I_D = -250 \ \mu A & -2.0 & & -4.0 \\ \hline \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \$ |

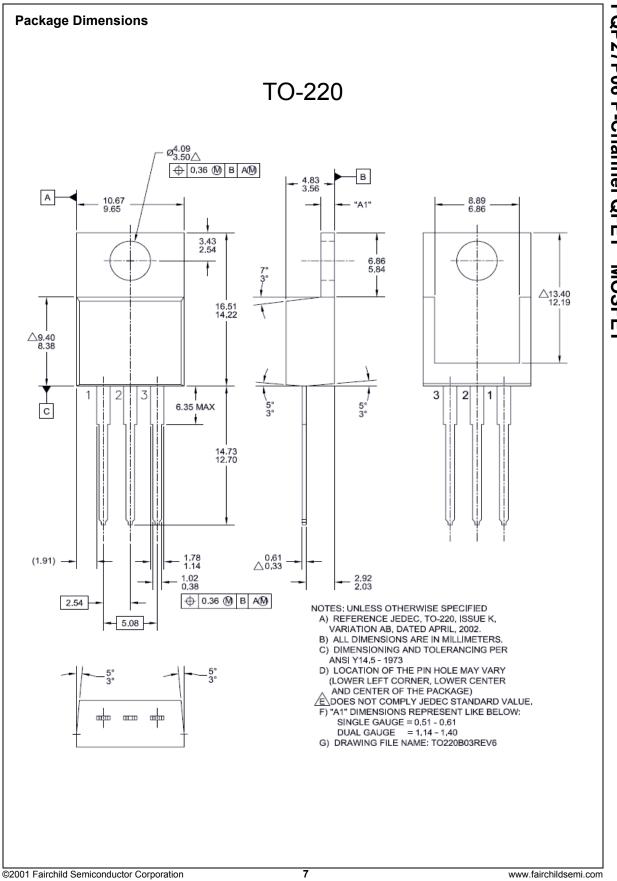


FQP27P06 Rev.C0









FQP27P06 P-Channel QFET® MOSFET



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